

## FIG. 1

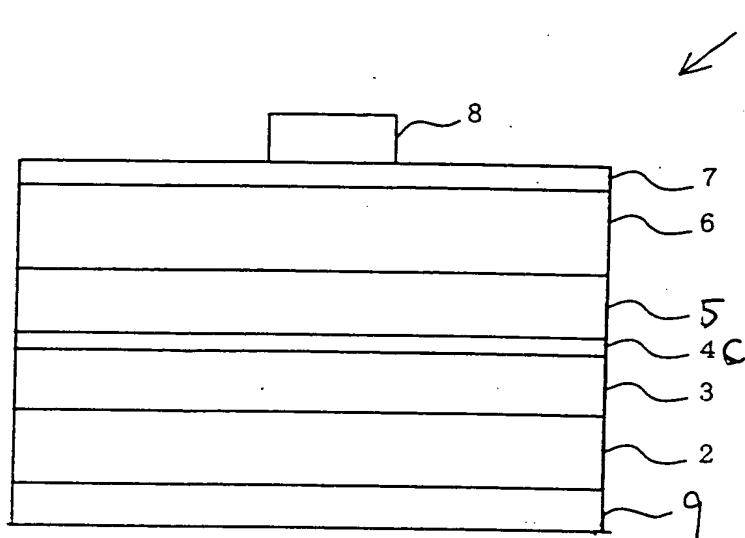


FIG. 2

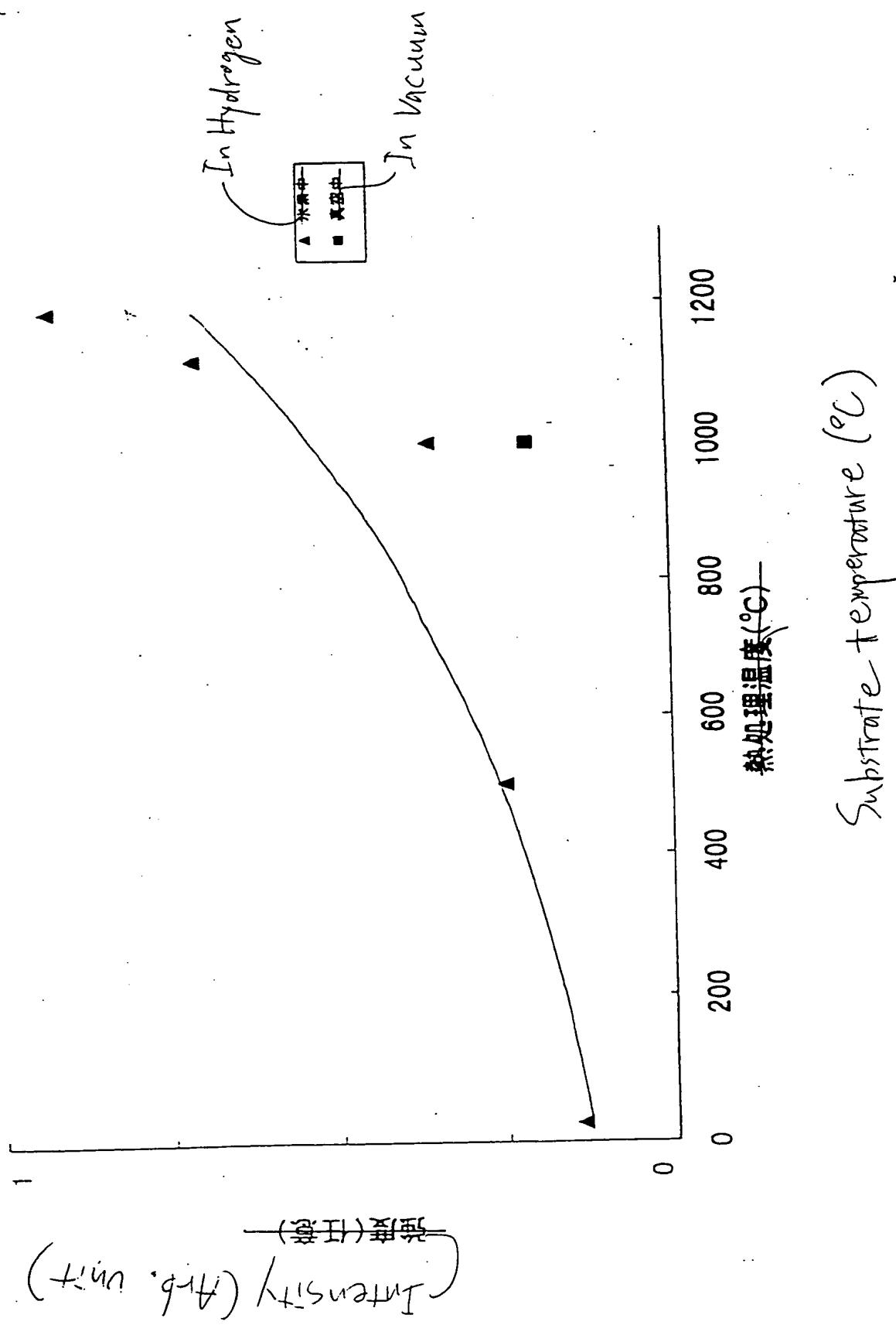


Fig. 3

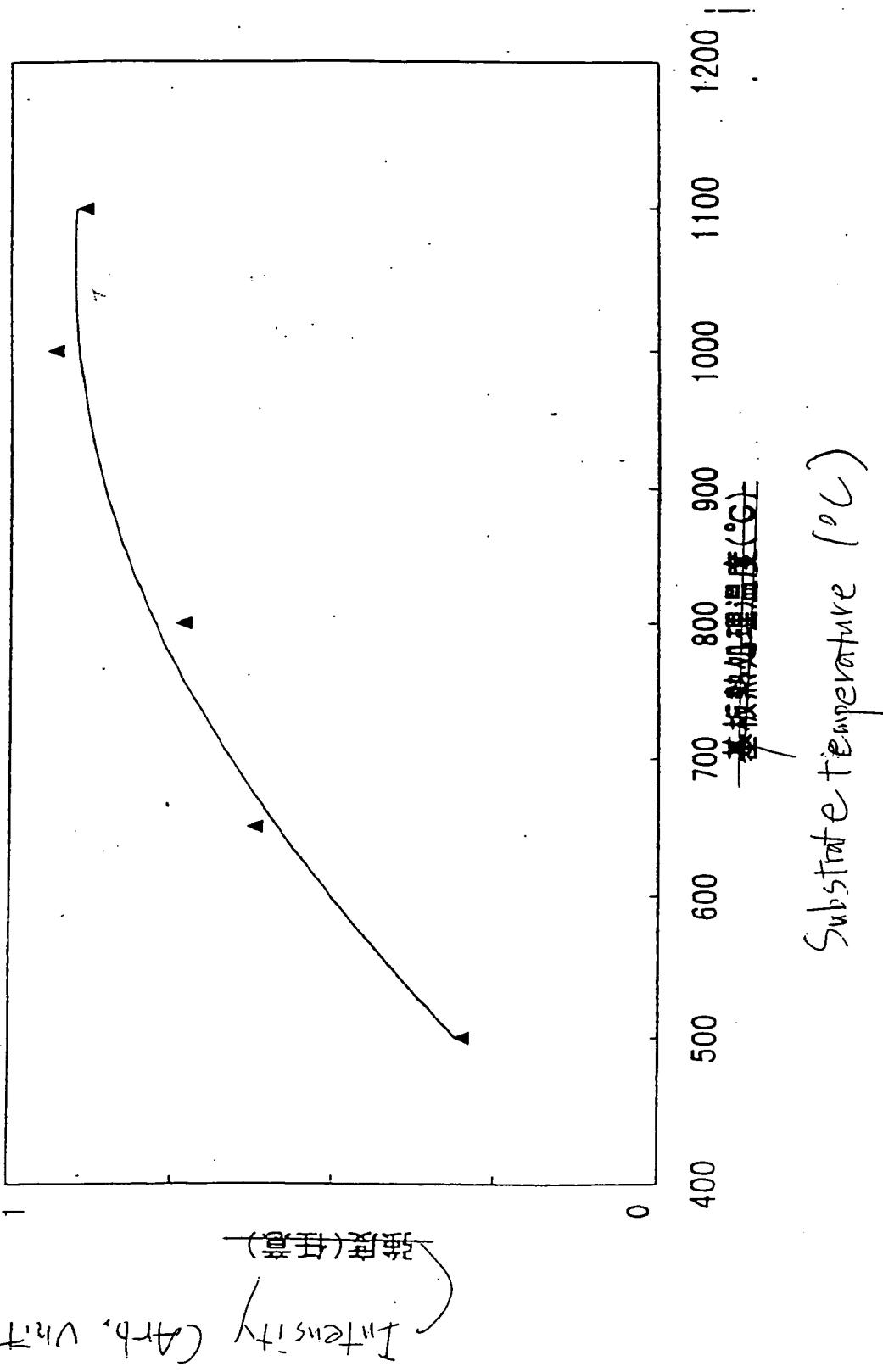


FIG. 4

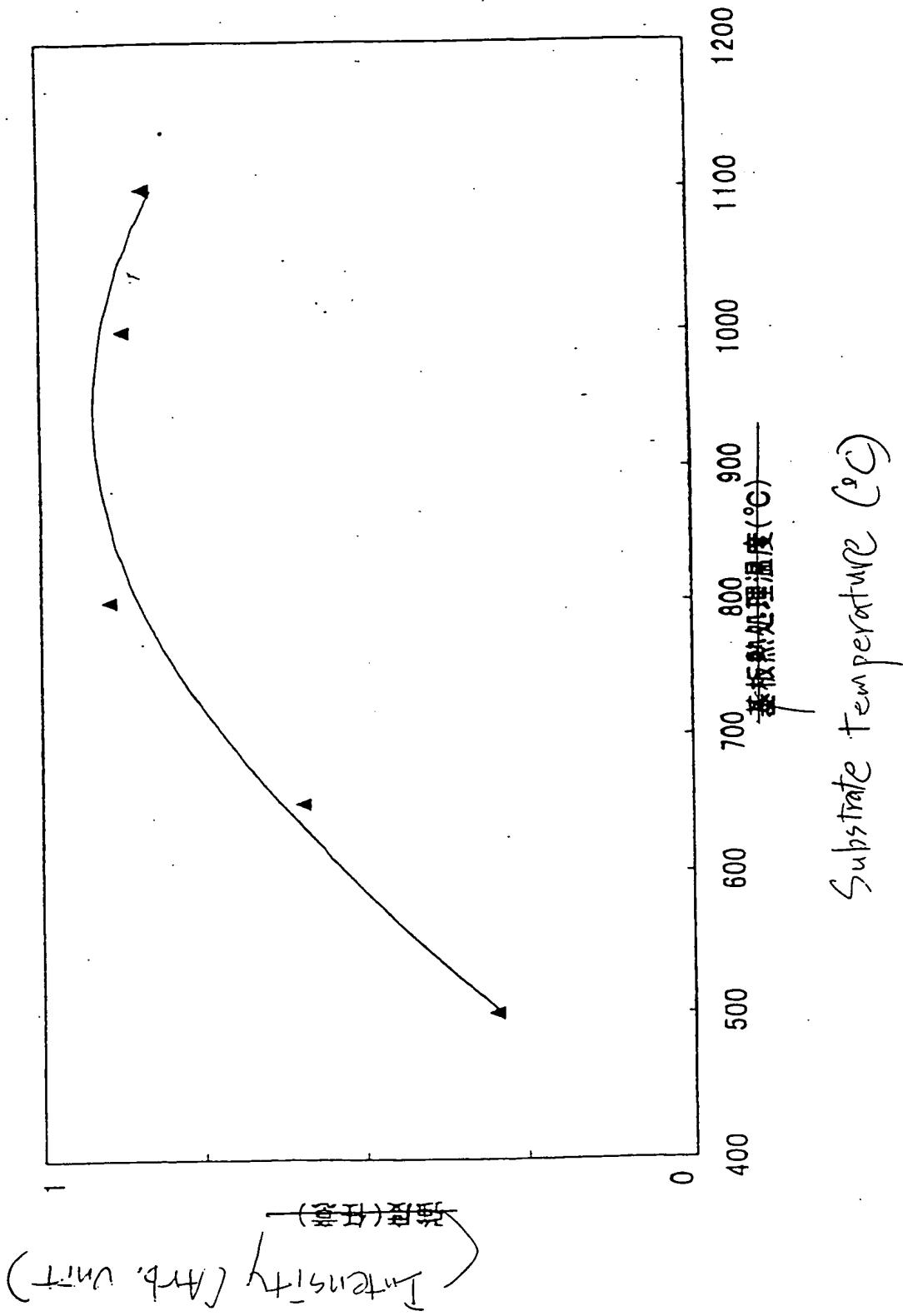


FIG. 5

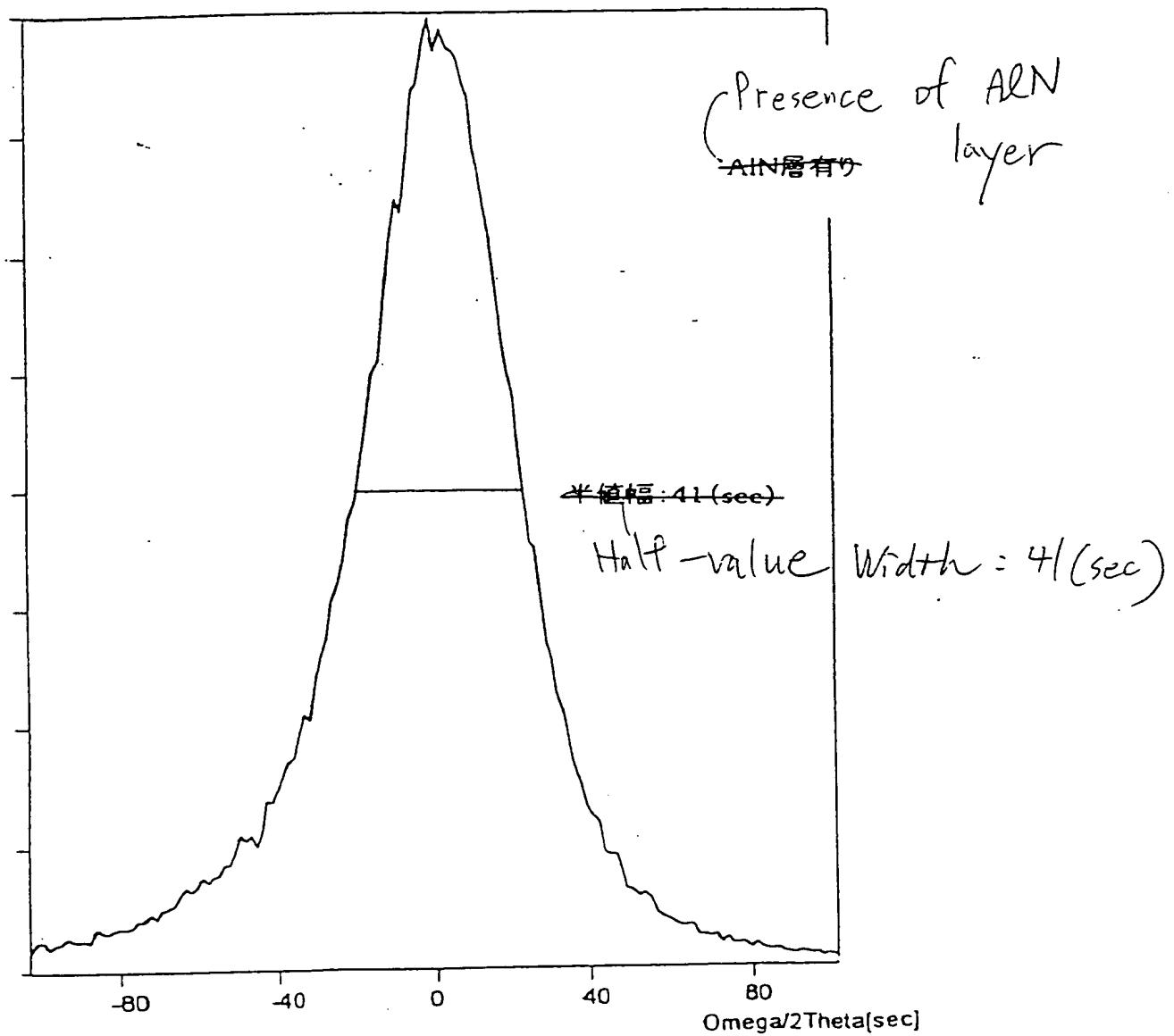


FIG. 6

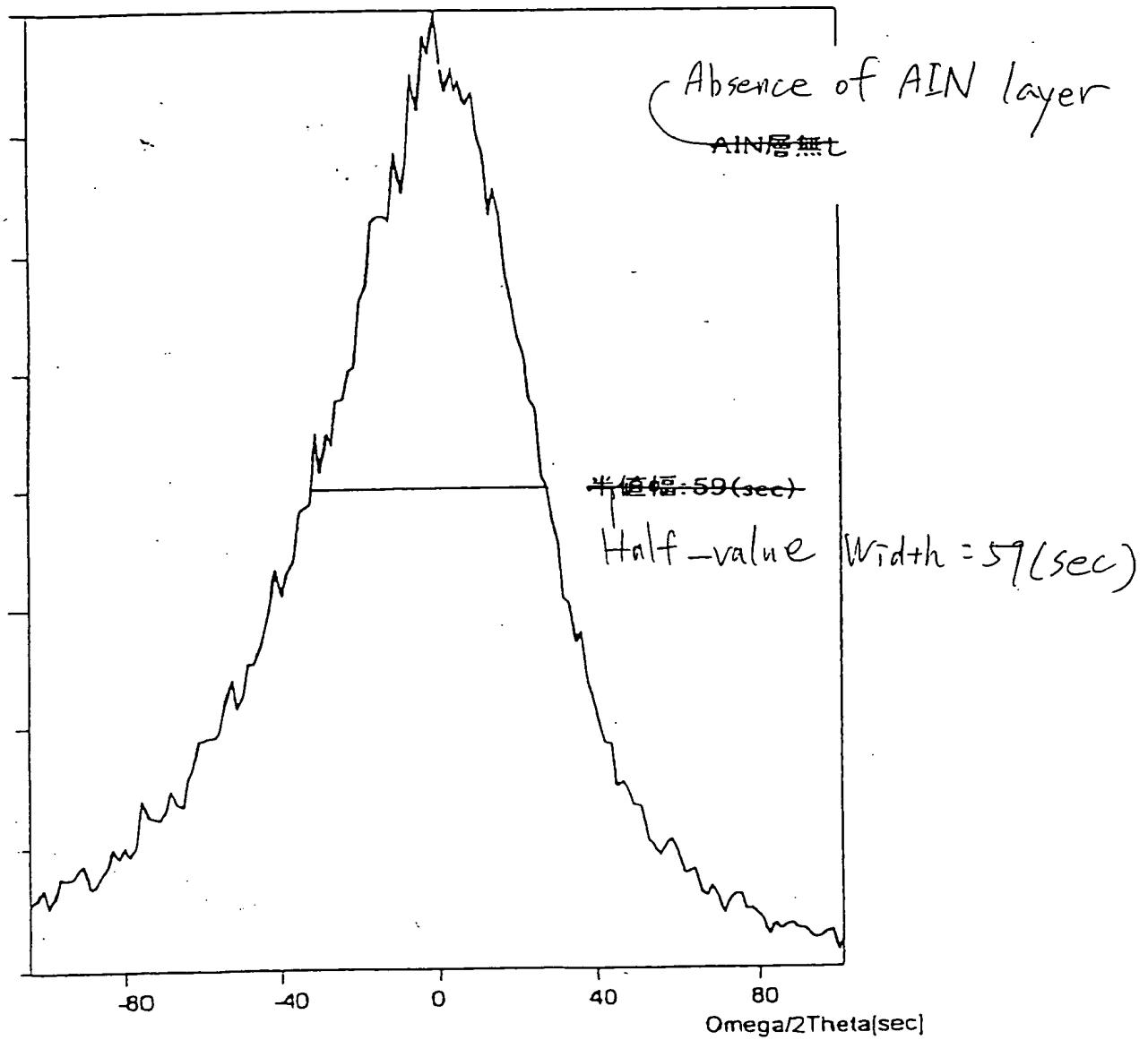
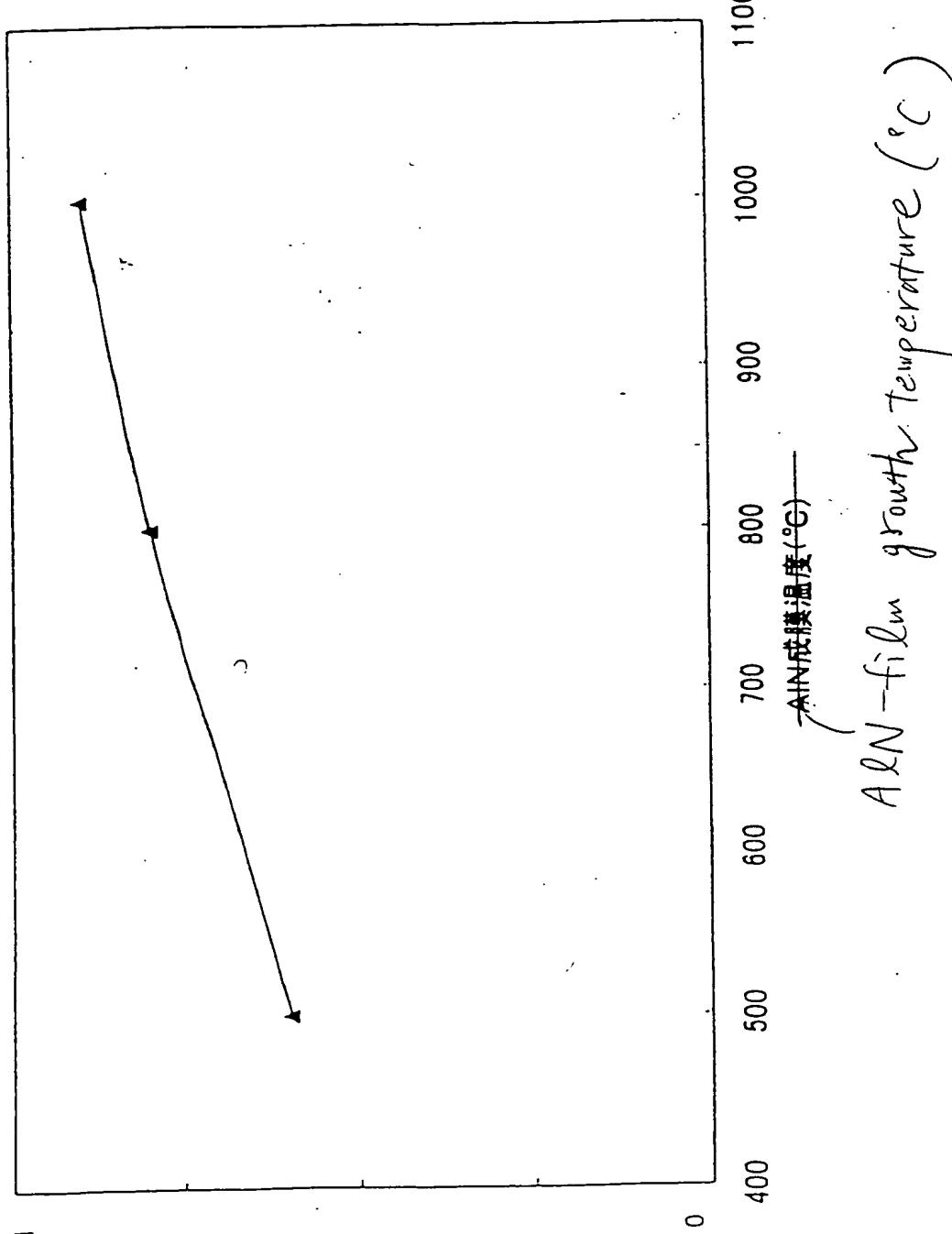


FIGURE 03402007

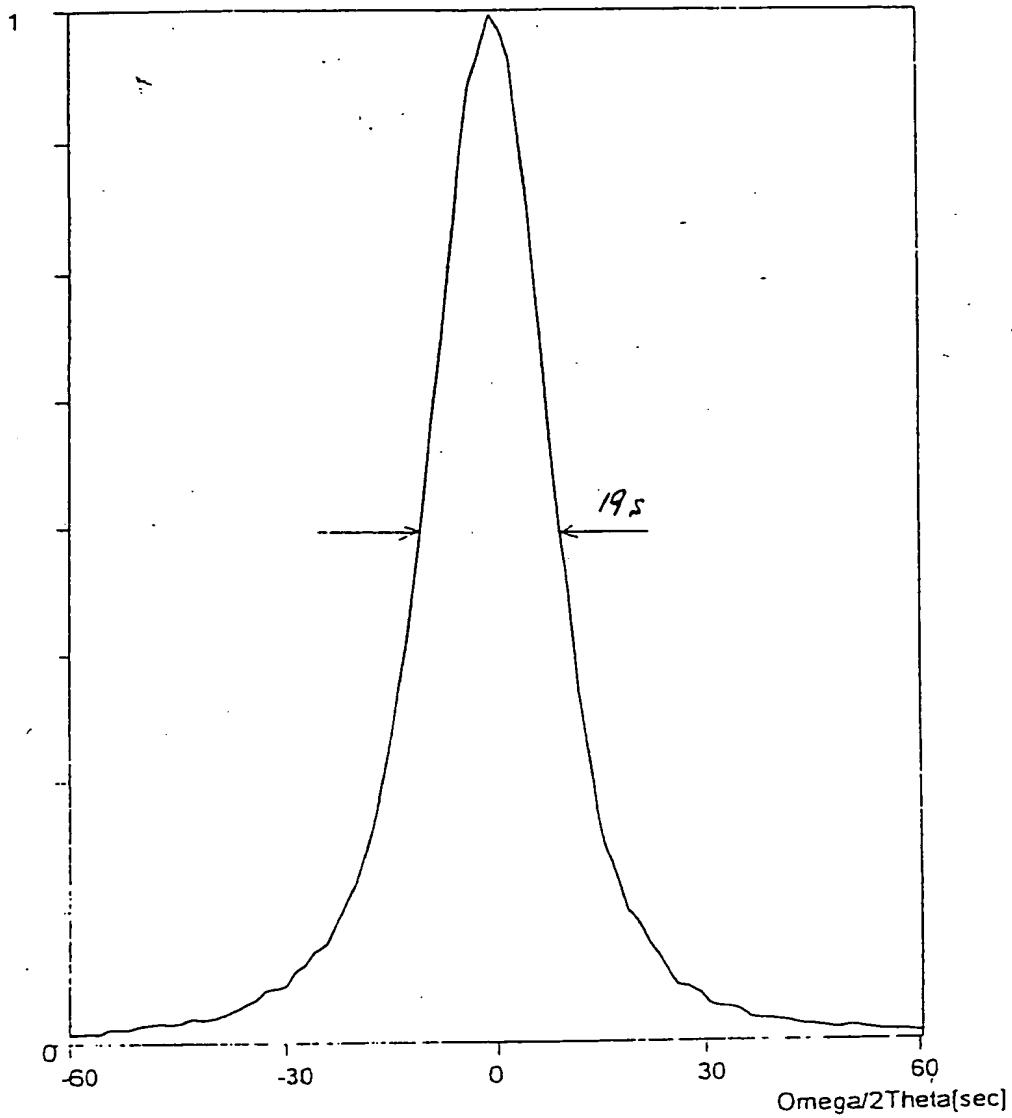
FIG. 7



Lattice constant (Å)  
AIN-film growth temperature (°C)

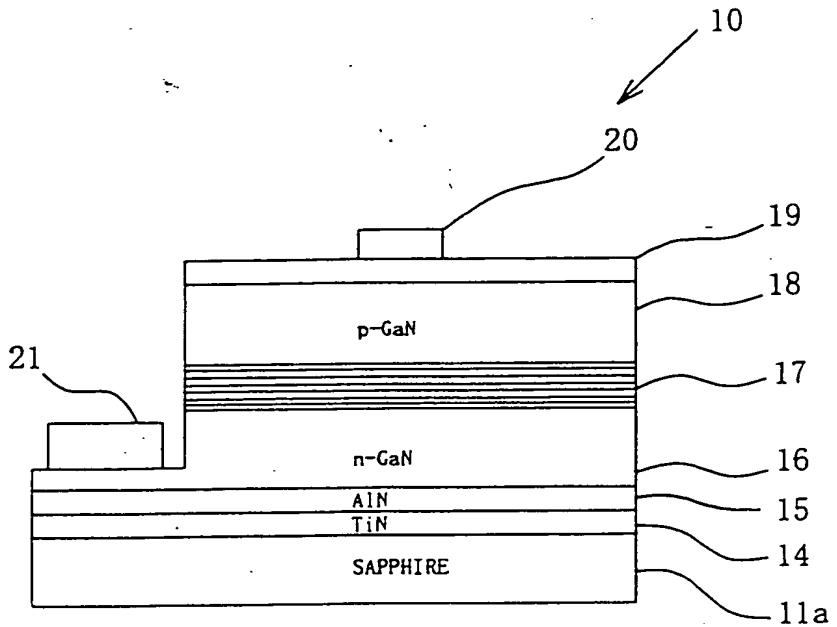
FIG. 8

X-ray rocking curve  
of GaN  
GaN の X 線 ロッキング カーブ  
GaN / AlN / TiN / Sap



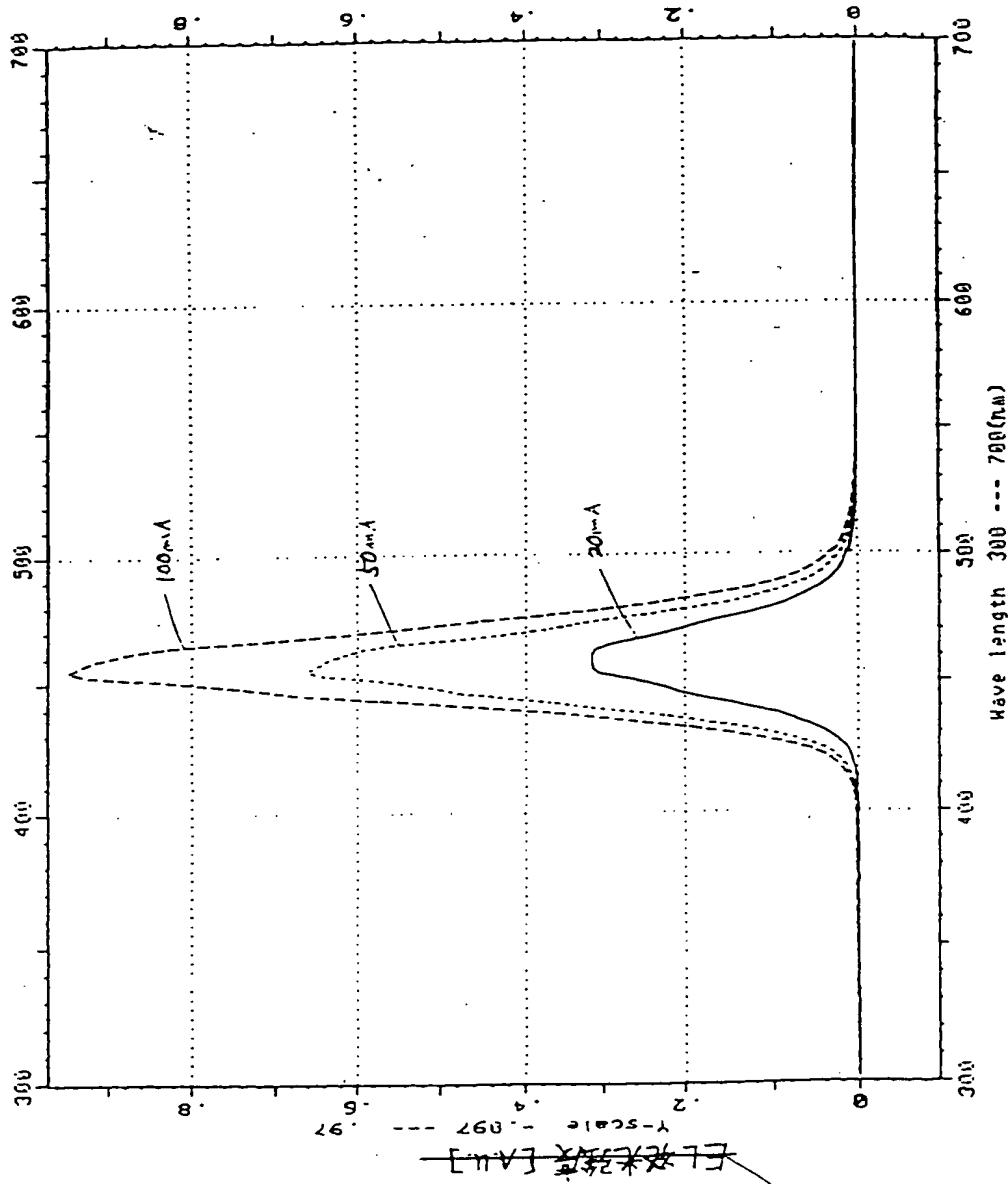
1002046-0-12301

FIG. 9



1000450-12402002

Fig. 10



Emission Light Intensity (A.U.)

FIG. 11

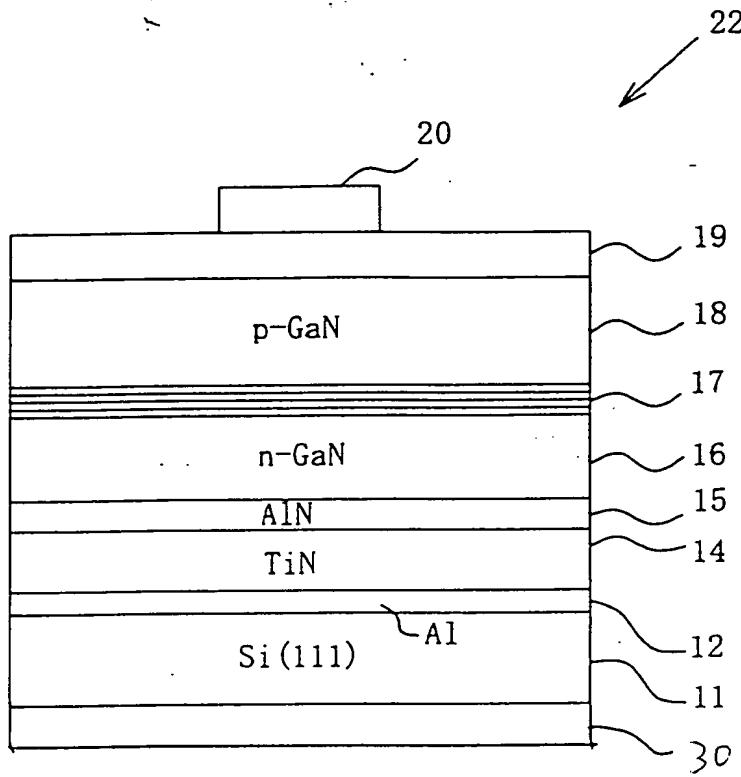


FIG.12

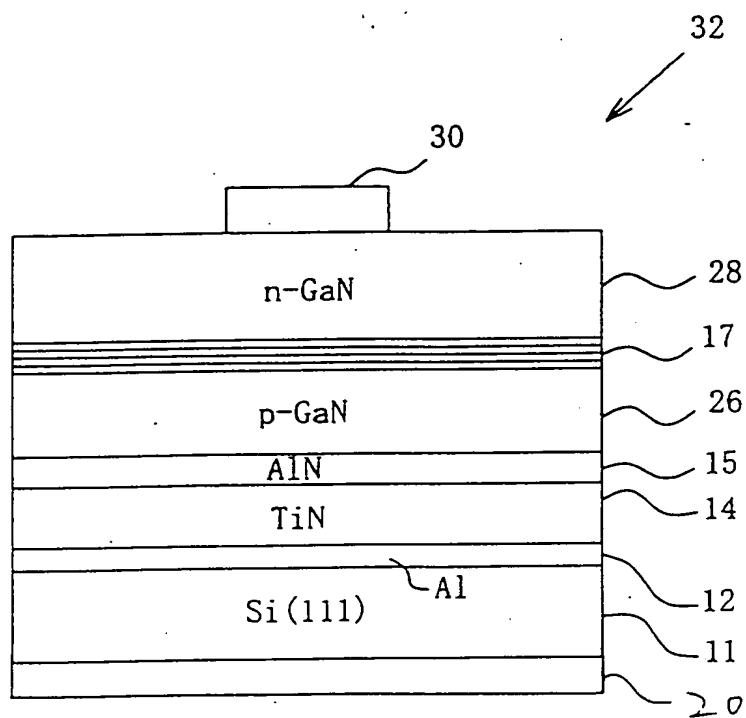
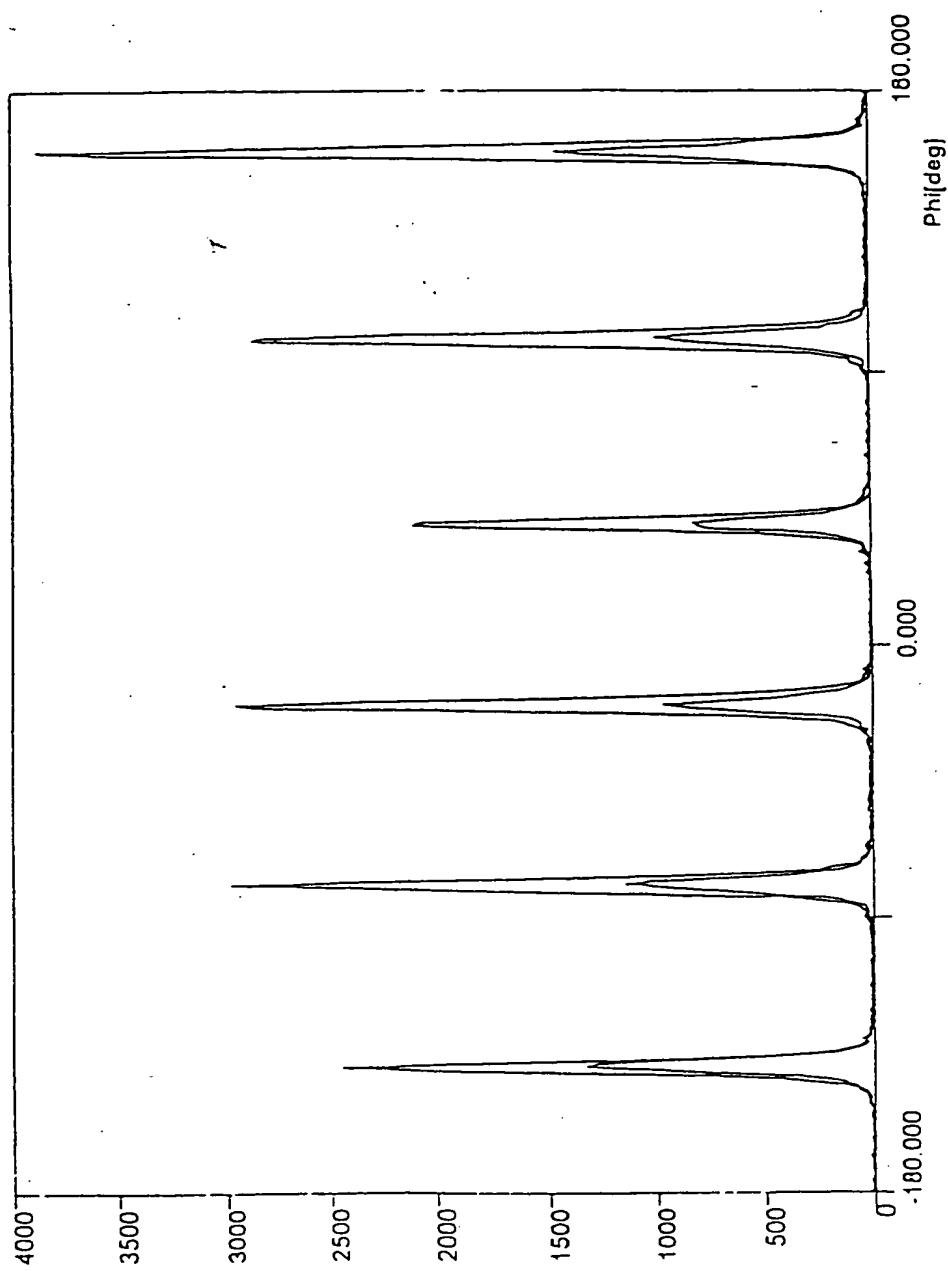
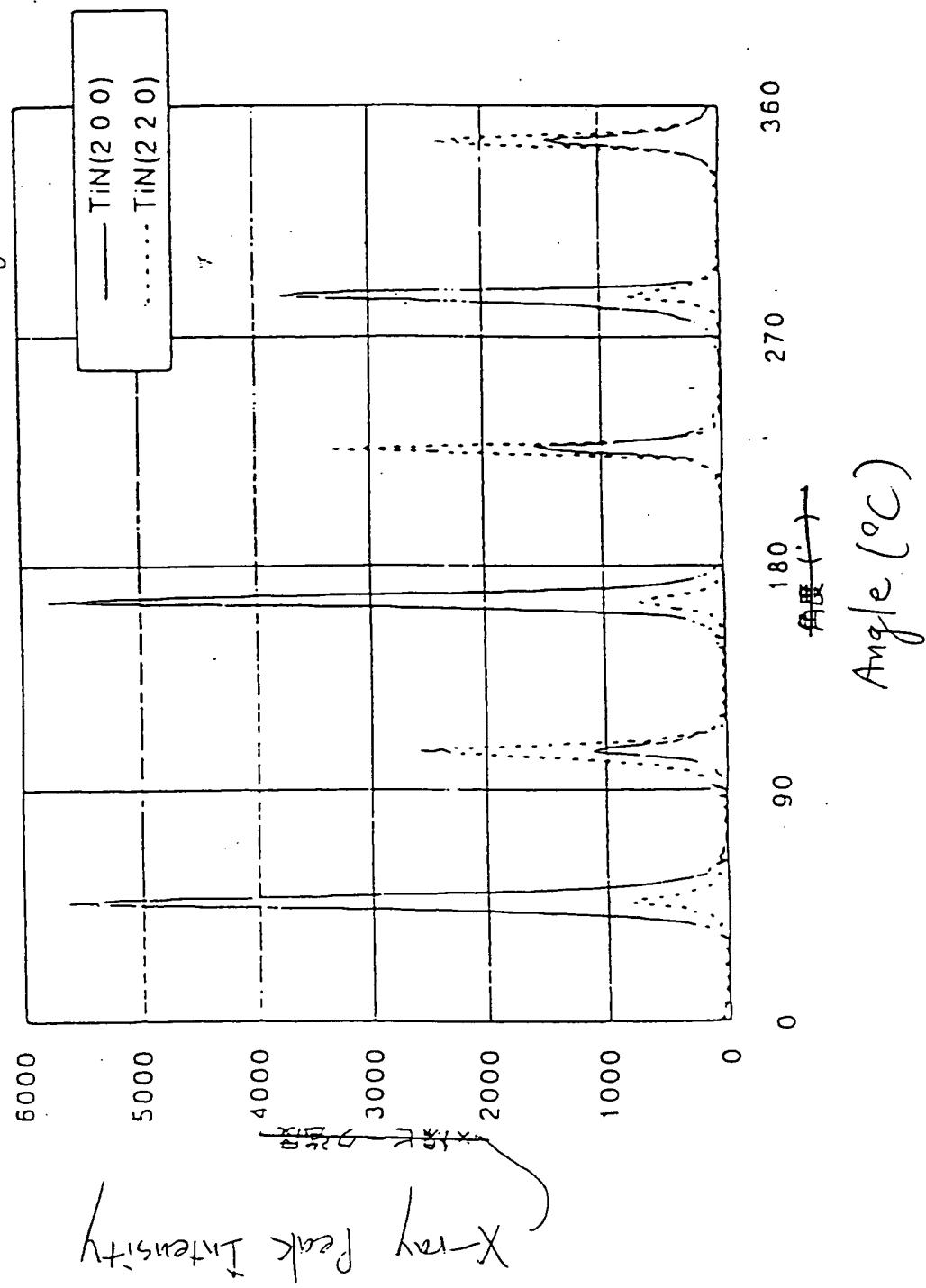


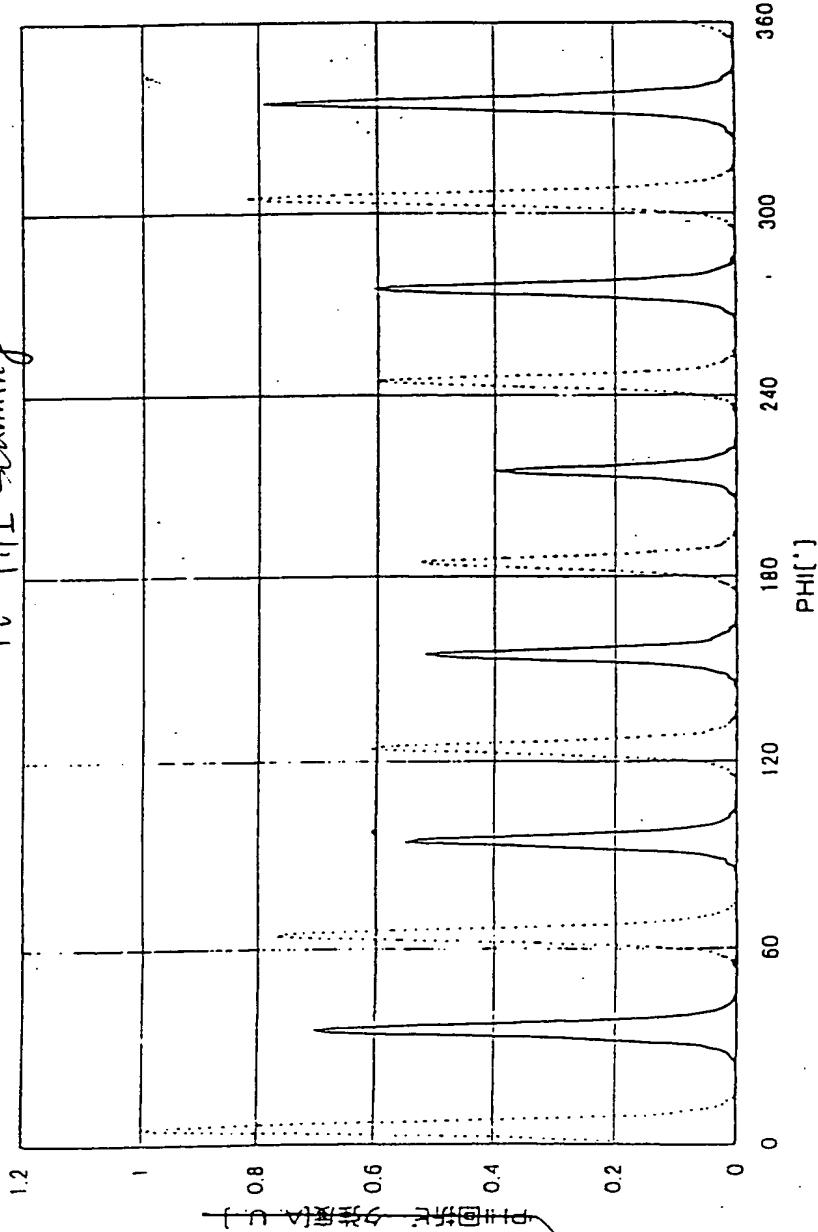
Fig. 13





Ti(15000Å)/TiN(5000Å)/Al/Si

PHI Scanning



PHI Diffraction Peak Intensity (A.u.)

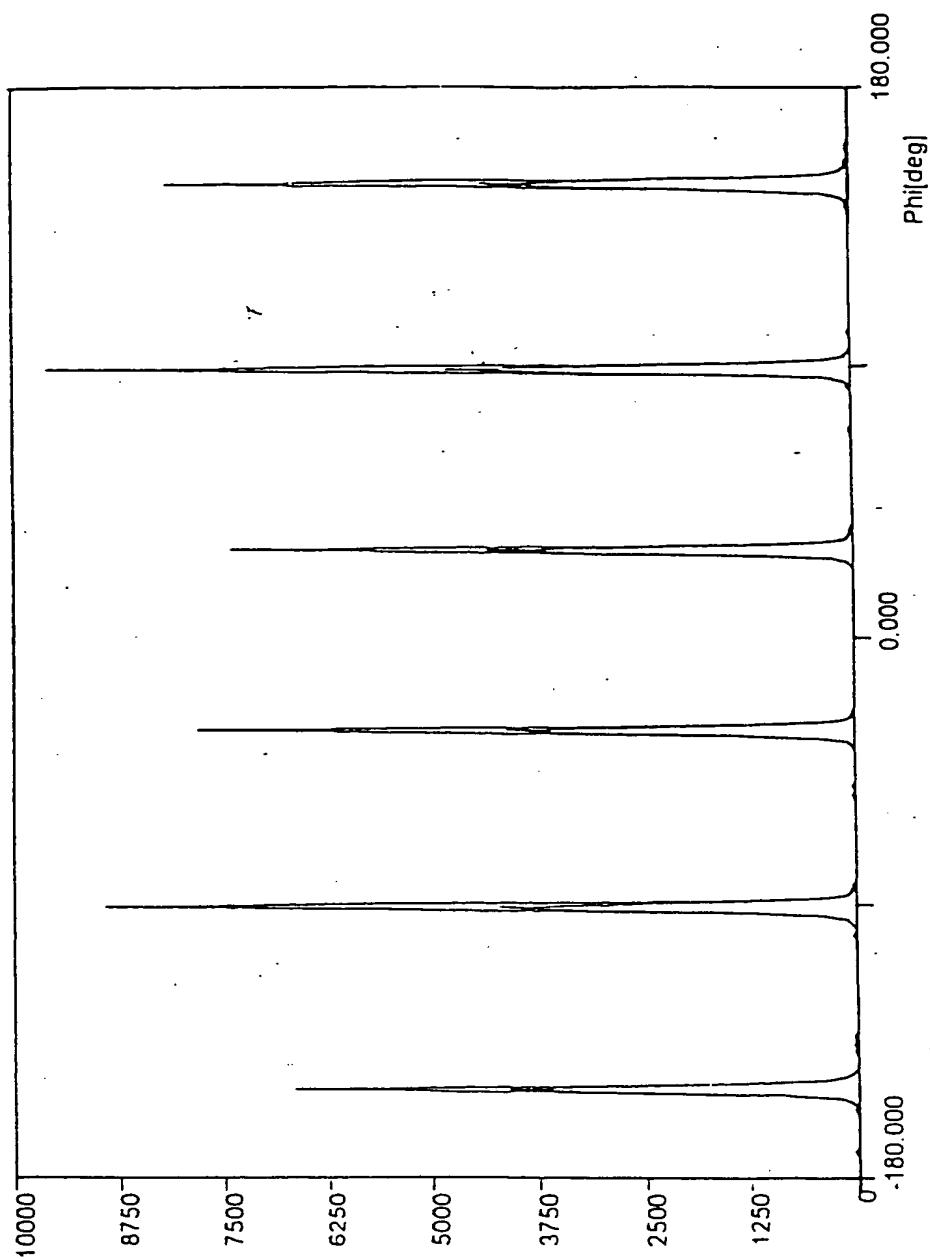
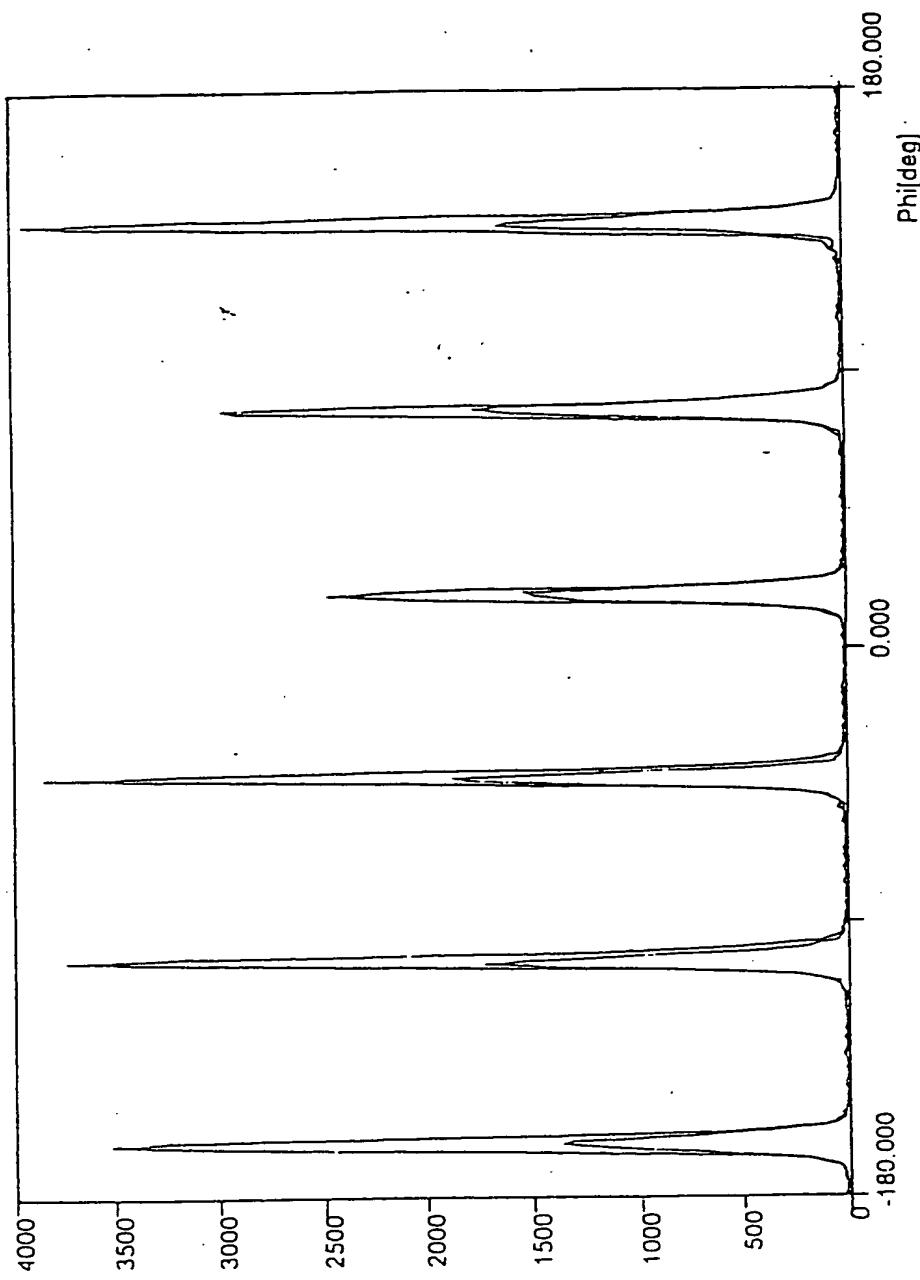
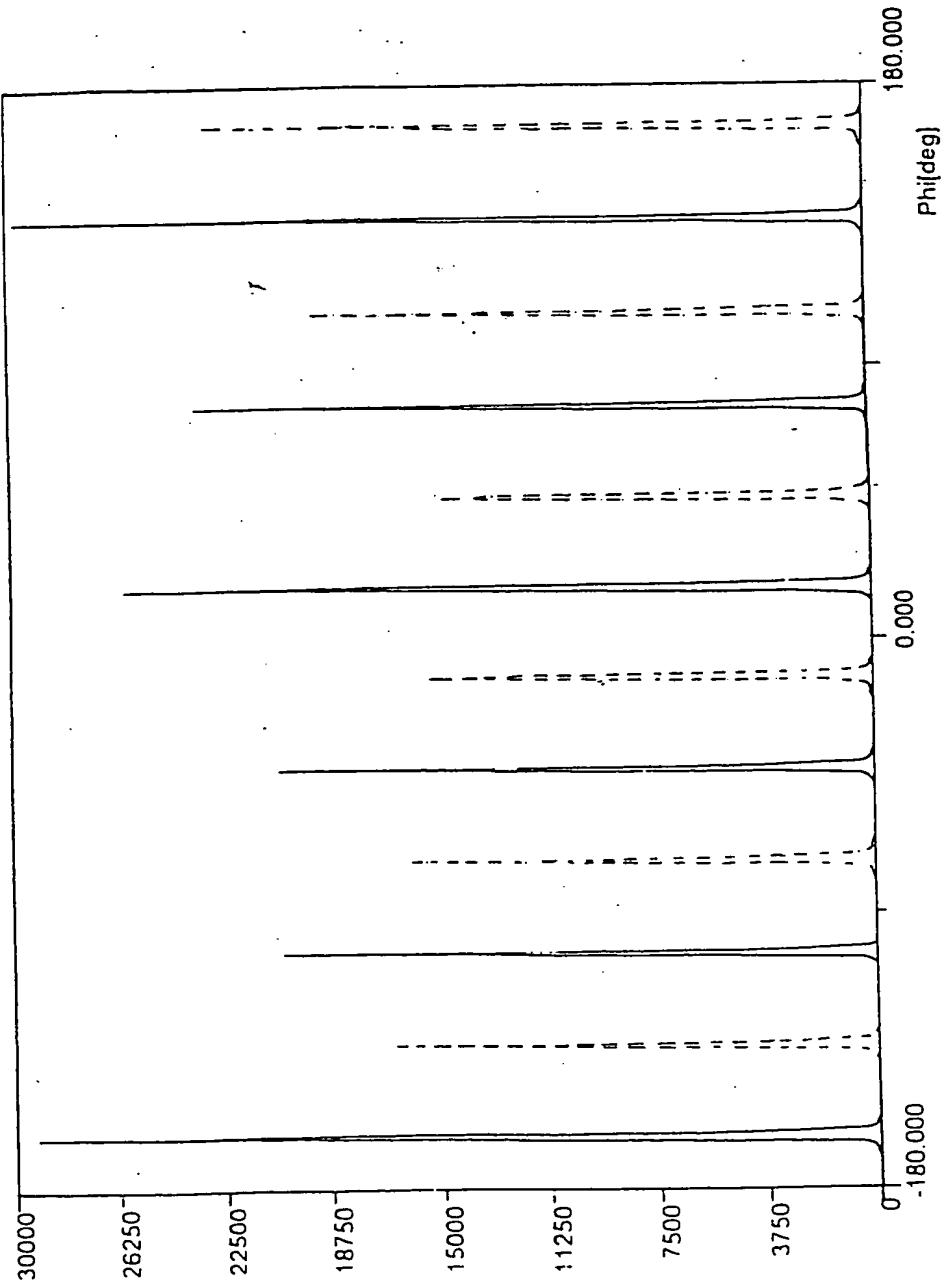
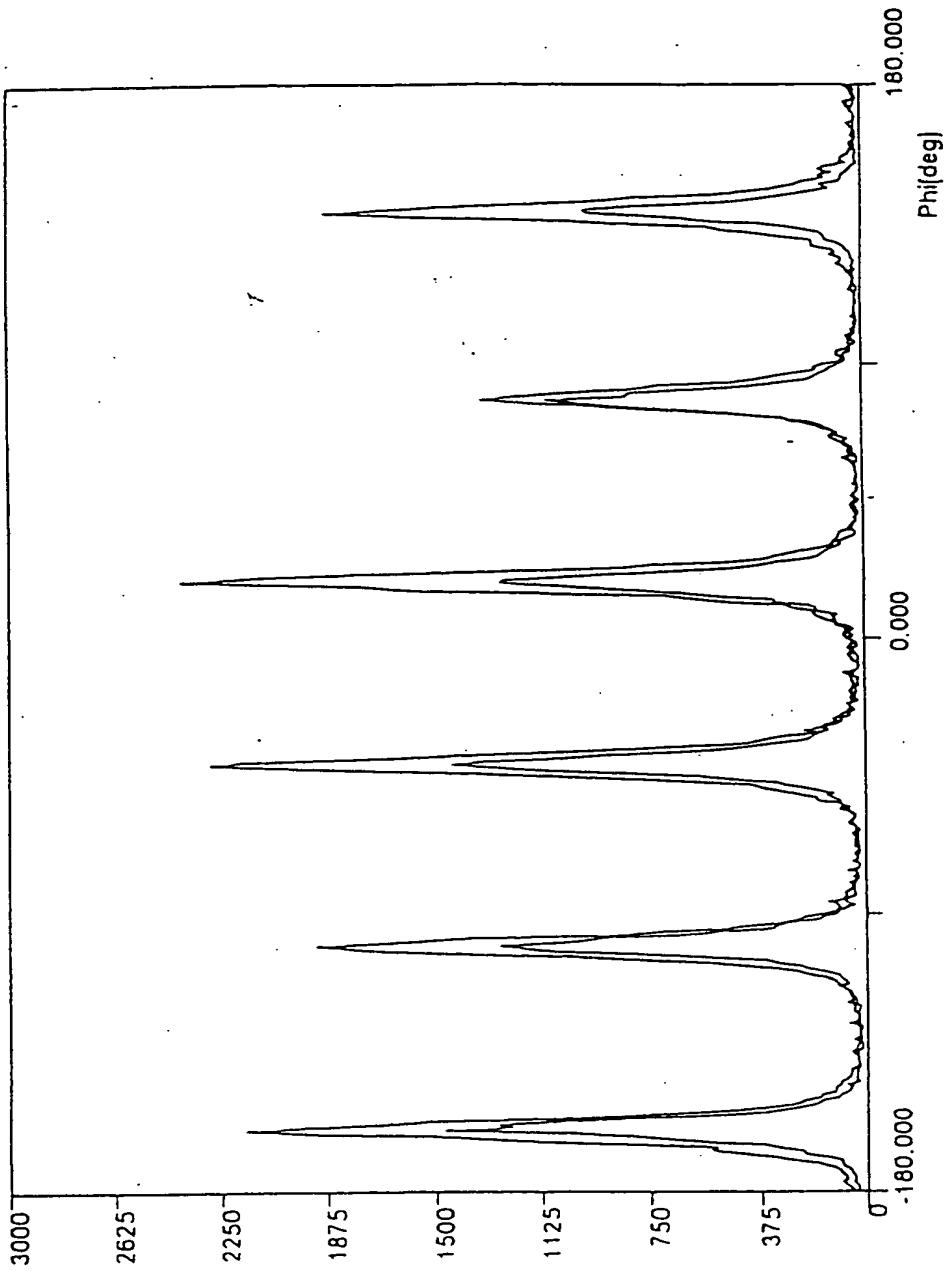


FIG. 16

1003 F2T 10 94 02 08  
FIG. 17





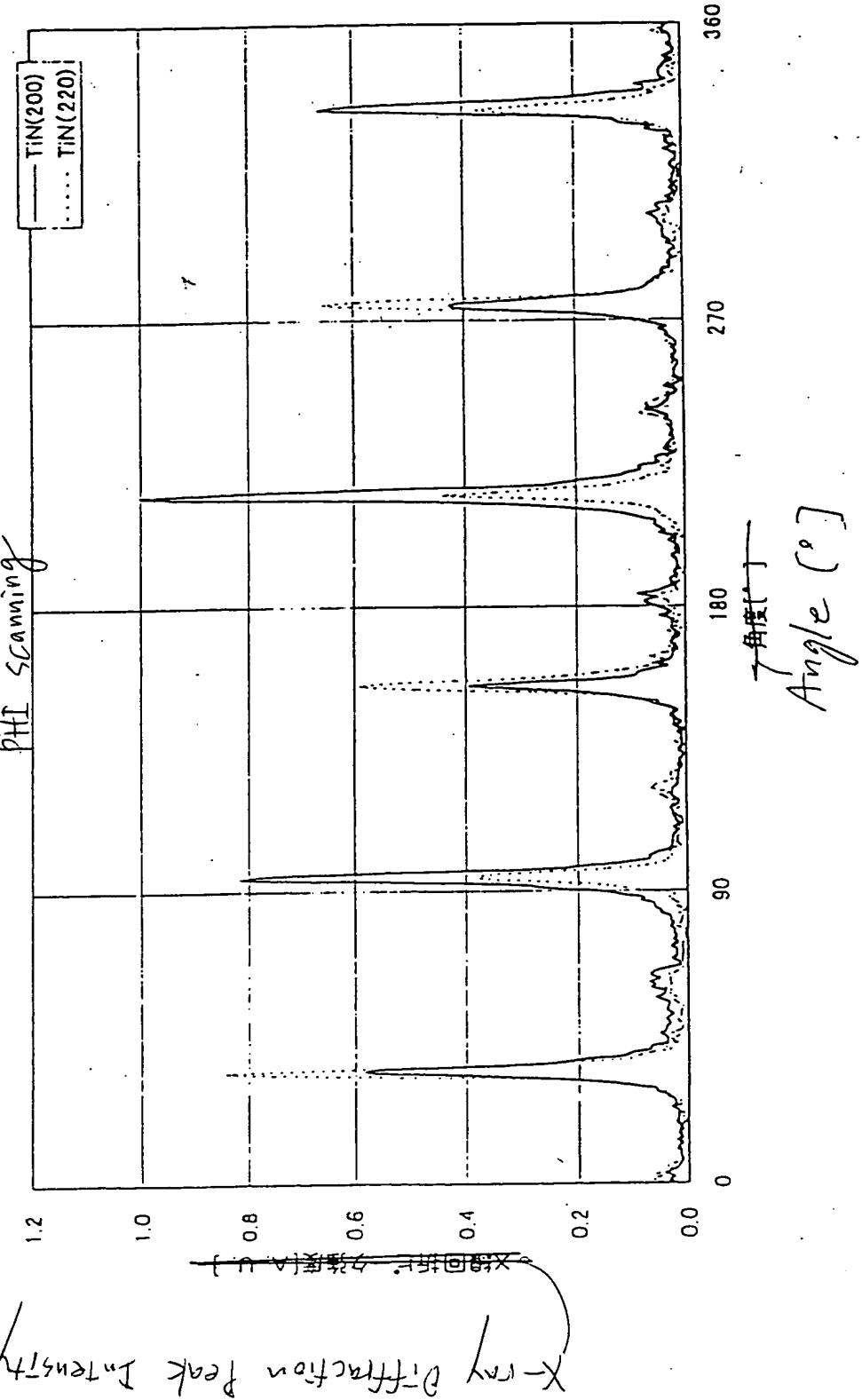
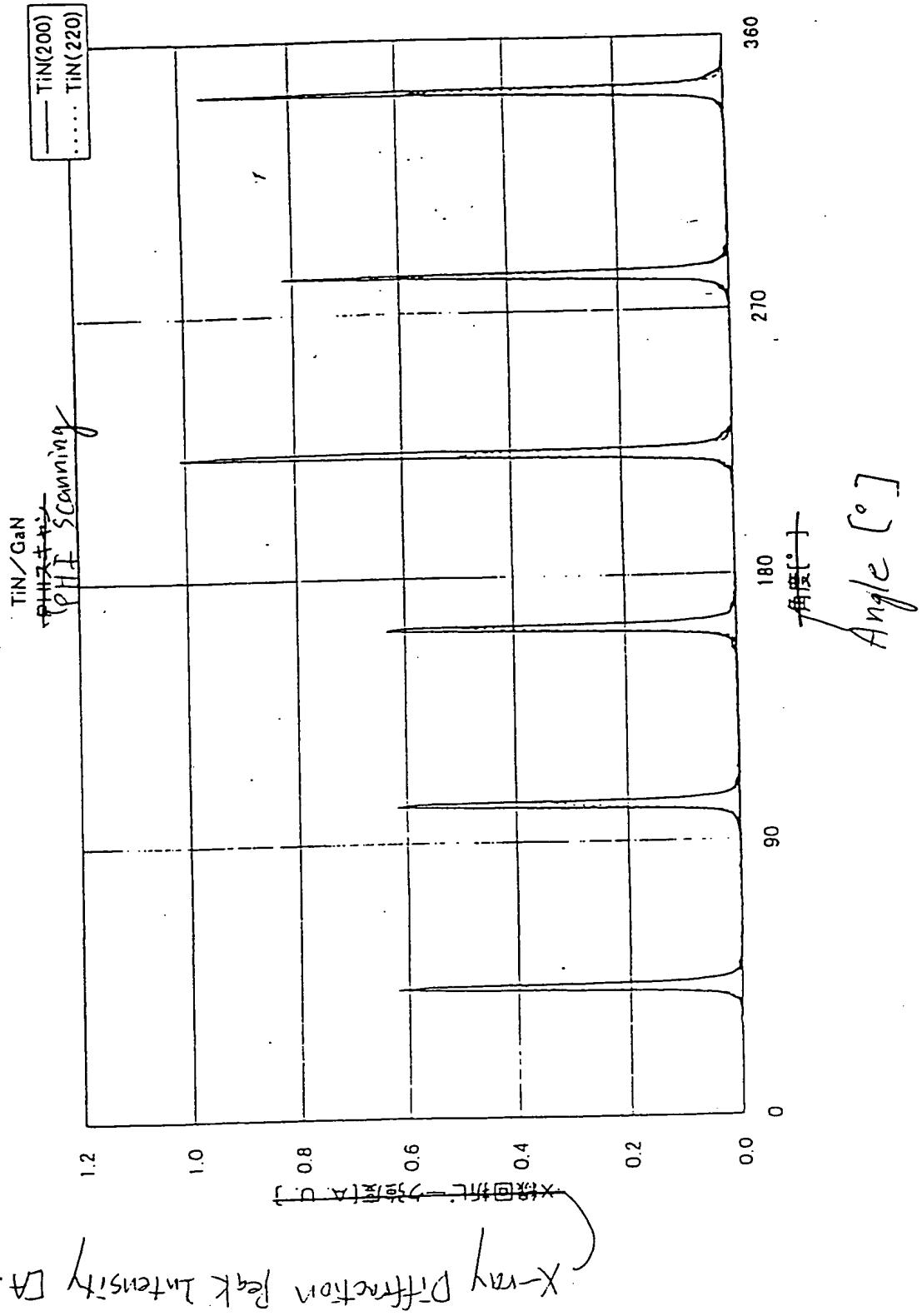
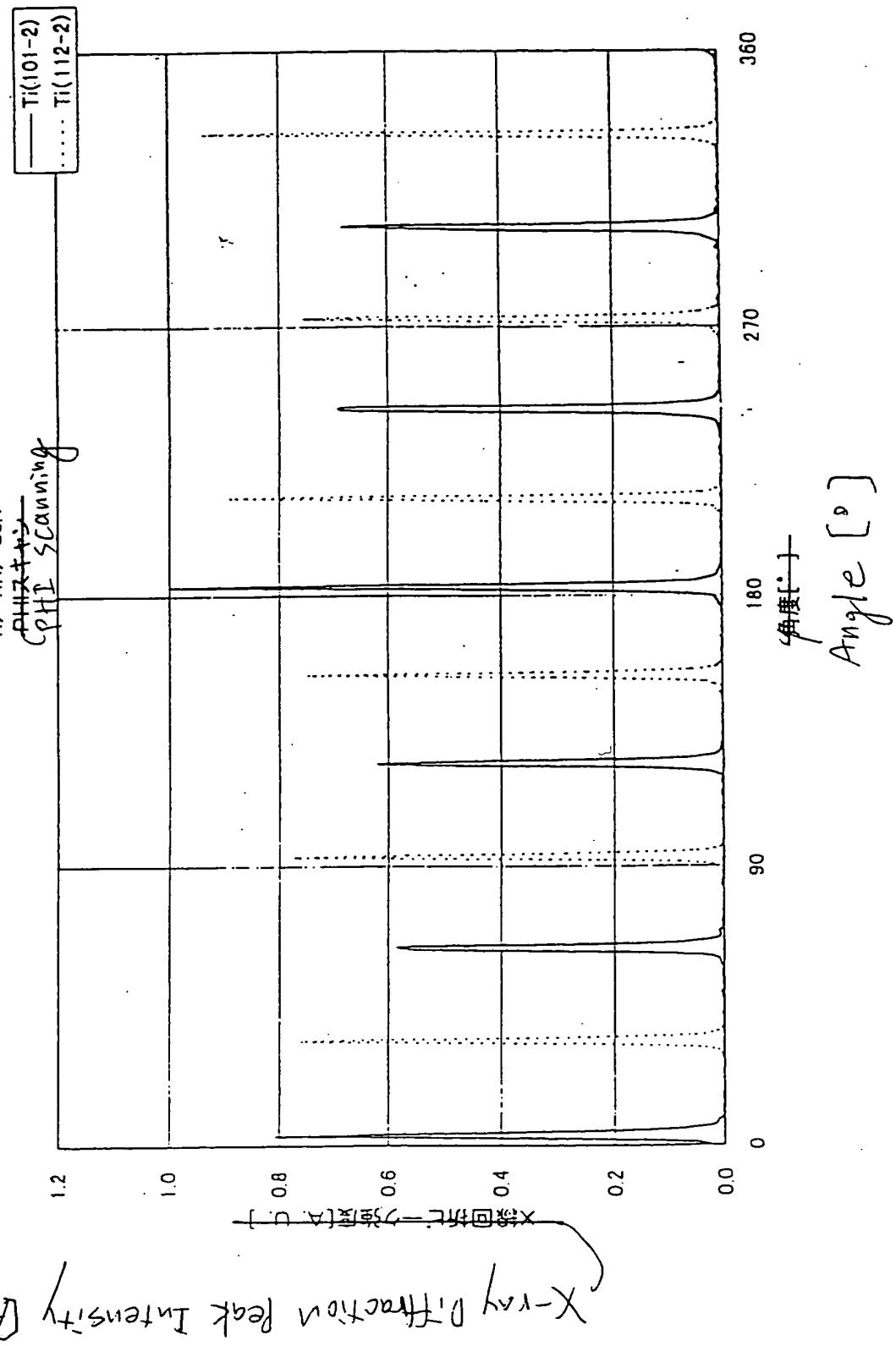


FIGURE 21 - OSG-0008



X-ray Diffraction Peak Intensity [A.m.u.]



X-ray Diffraction Peak Intensity (A.U.)

FIG. 23

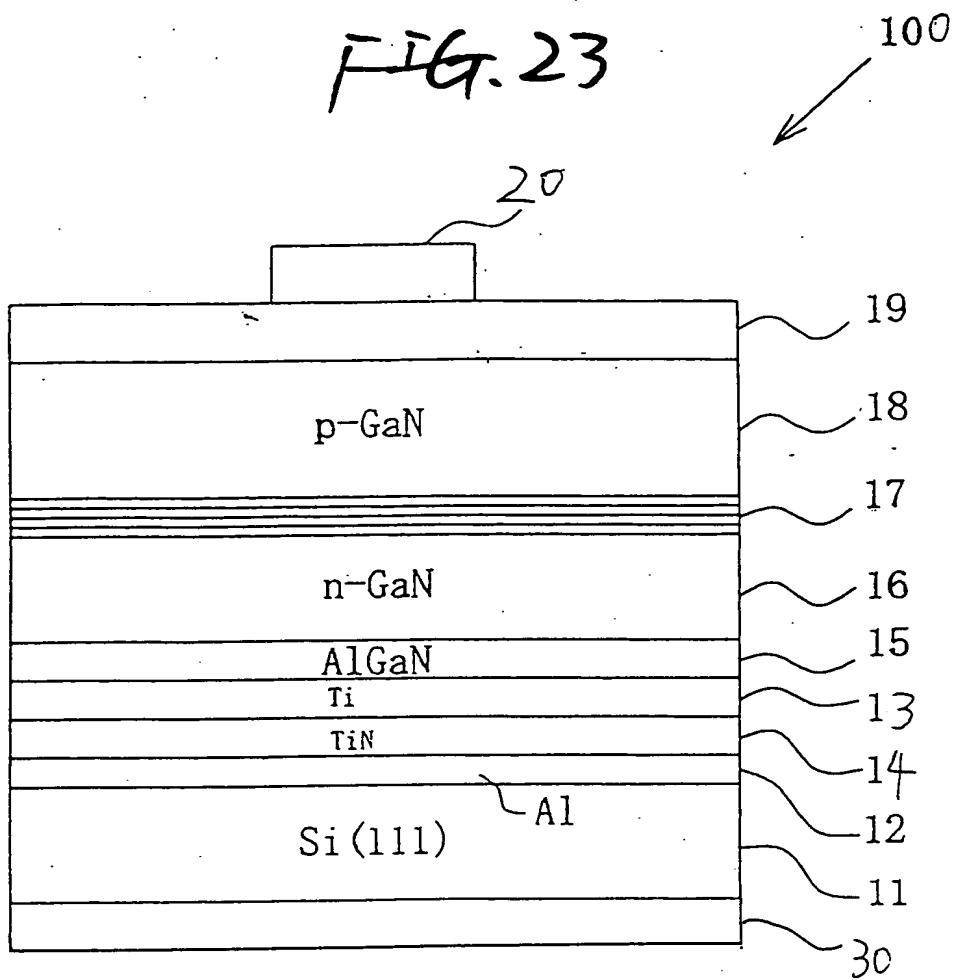


FIG. 24

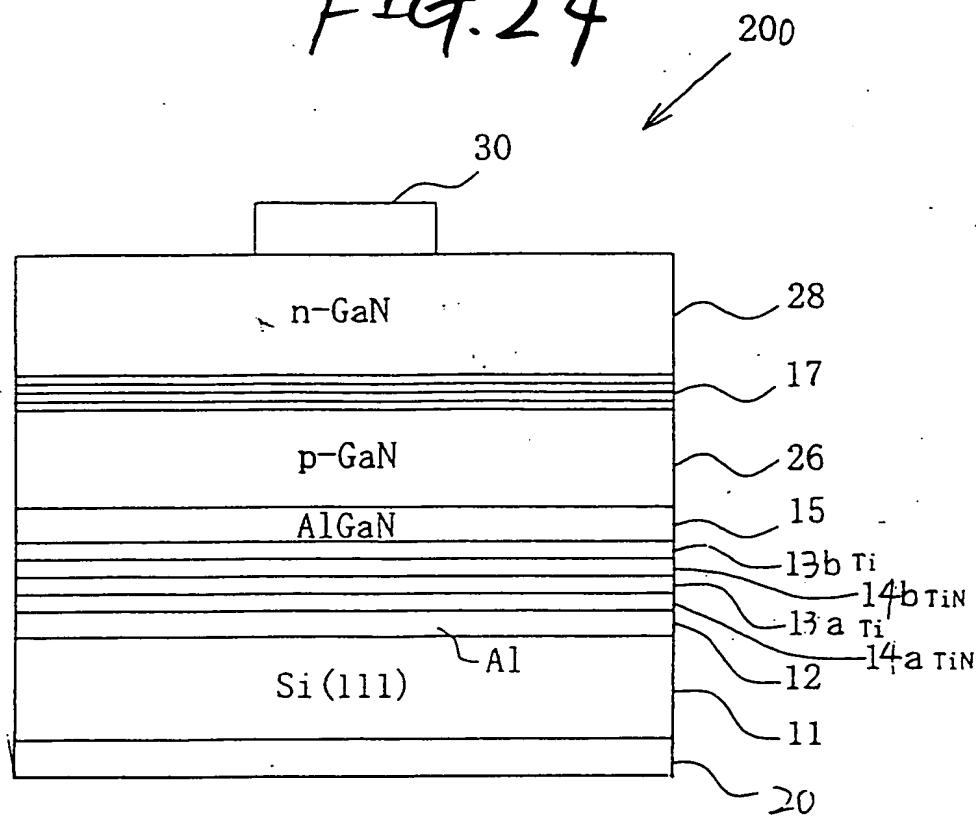


FIG. 25

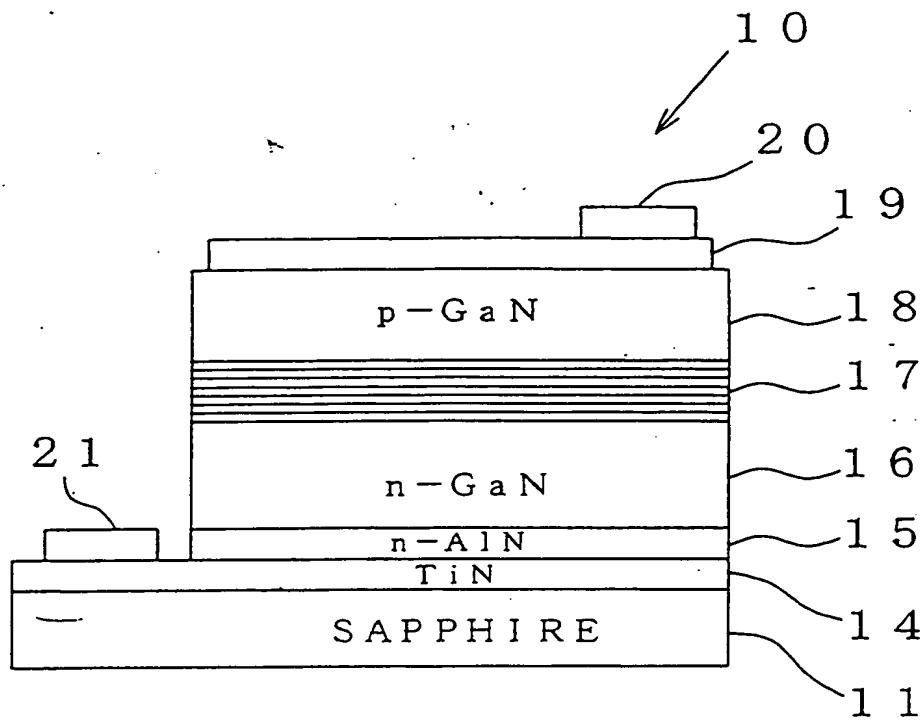


FIG. 26

